



US00D918011S

(12) **United States Design Patent** (10) **Patent No.:** **US D918,011 S**  
**Sambu et al.** (45) **Date of Patent:** **\*\* May 4, 2021**

(54) **DOOR LATCH FOR SEMICONDUCTOR MANUFACTURING EQUIPMENT**

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(\*\*) Term: **15 Years**

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(30) **Foreign Application Priority Data**

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(51) **LOC (13) Cl.** ..... **08-07**

(52) **U.S. Cl.**  
USPC ..... **D8/331**

(58) **Field of Classification Search**

USPC ..... D8/330-333, 336, 338, 343-346, D8/300-302, 306-329; 70/91, 277, 336, 70/280, 14, 51, 52, 57.1, 67, 69, 78, 85, 70/86, 88, 141; 292/340-346, 180

CPC ..... B23K 31/02; B23K 37/00; H01R 33/76; H01R 12/58; G01R 1/073; G01R 31/26; G01R 1/0433; G01R 1/0466; G01R 31/2601; G01R 31/2867; G01R 31/2893; G01R 31/01; H01L 22/30; H01L 21/67706; H01L 21/66; H01L 21/687; E05B 69/003; E05B 71/00; E05B 73/005; E05B 17/142; E05B 47/0011; E05B 47/00; E05B 41/00; E05B 47/06; E05B 47/0001; E05B 47/0615; E05B 47/0012; E05B 15/02; E05B 65/466; E05B 65/469; E05B 13/001; E05B 13/007;

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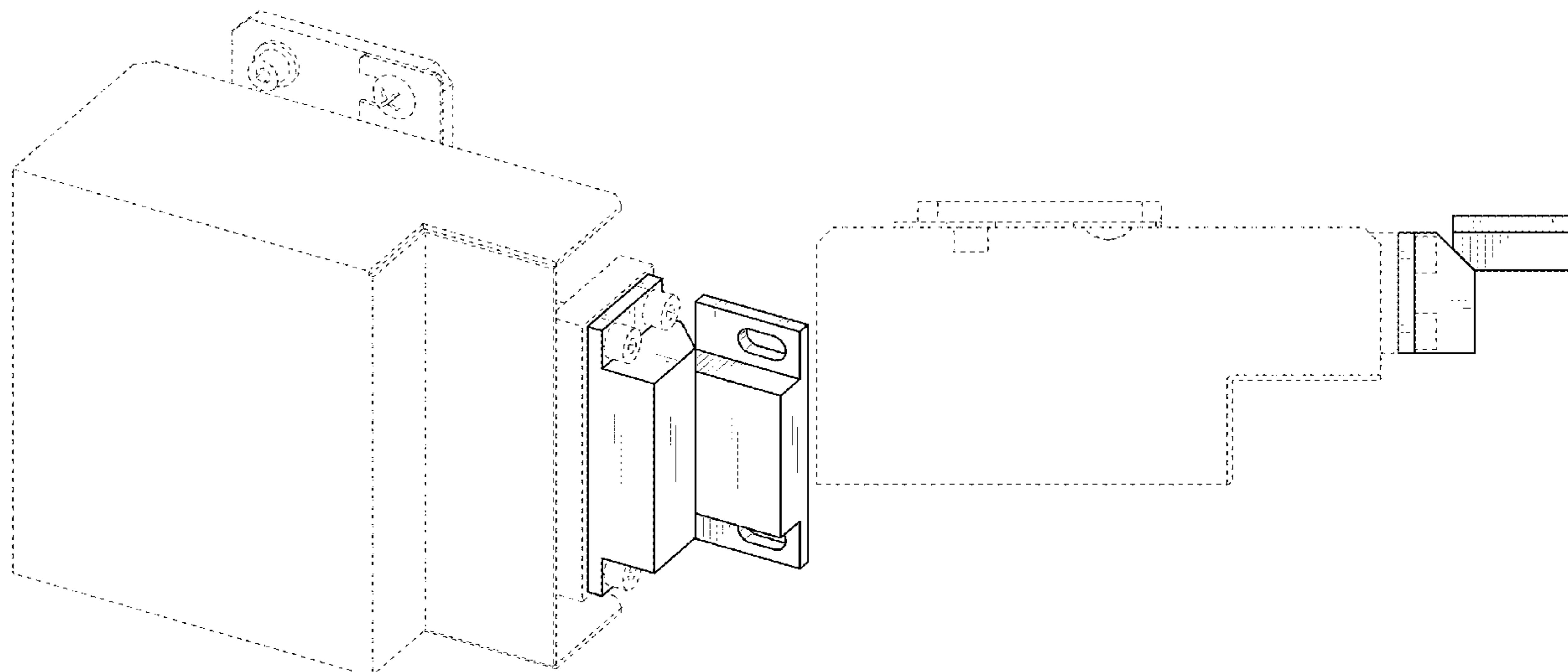
(57) **CLAIM**

We claim the ornamental design for a door latch for semiconductor manufacturing equipment, as shown and described.

**DESCRIPTION**

FIG. 1 is a front, top and right side perspective view of a door latch for semiconductor manufacturing equipment showing our new design;  
 FIG. 2 is a front elevational view thereof;  
 FIG. 3 is a left side elevational view thereof;  
 FIG. 4 is a right side elevational view thereof;  
 FIG. 5 is a top plan view thereof;  
 FIG. 6 is a bottom plan view thereof.  
 FIG. 7 is a rear elevational view thereof;  
 FIG. 8 is a cross-sectional view take along line 8-8 in FIG. 2 thereof; and,  
 FIG. 9 is a perspective illustration indicating the state that a lock was opened.  
 The broken lines are included for the purpose of illustrating portions of the article that form no part of the claimed design.

**1 Claim, 6 Drawing Sheets**



(58) **Field of Classification Search**

CPC ..... E05B 13/00; E05B 13/10; E05B 65/44;  
E05B 65/46; E05B 65/462; E05B 65/463;  
E05B 65/461; E05B 65/464; E05B 51/00;  
E05B 35/00; E05B 39/00; E05B 17/14;  
E05B 2047/0086; B62H 5/001; Y10T  
70/5155; Y10T 70/5199; A47F 3/00;  
A47F 3/005; A47F 3/007; A47F 7/024;  
G07C 9/00563

See application file for complete search history.

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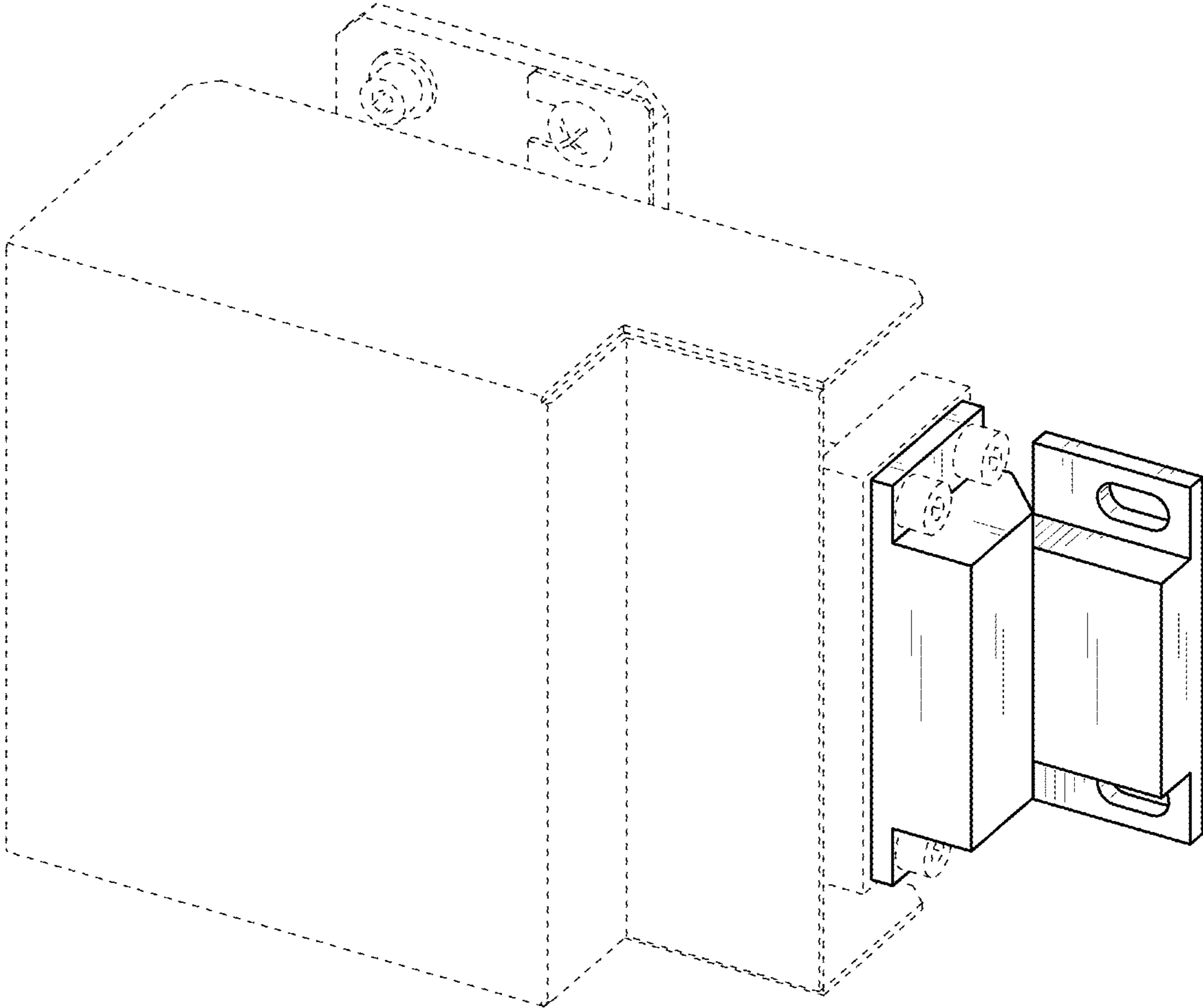


FIG. 1

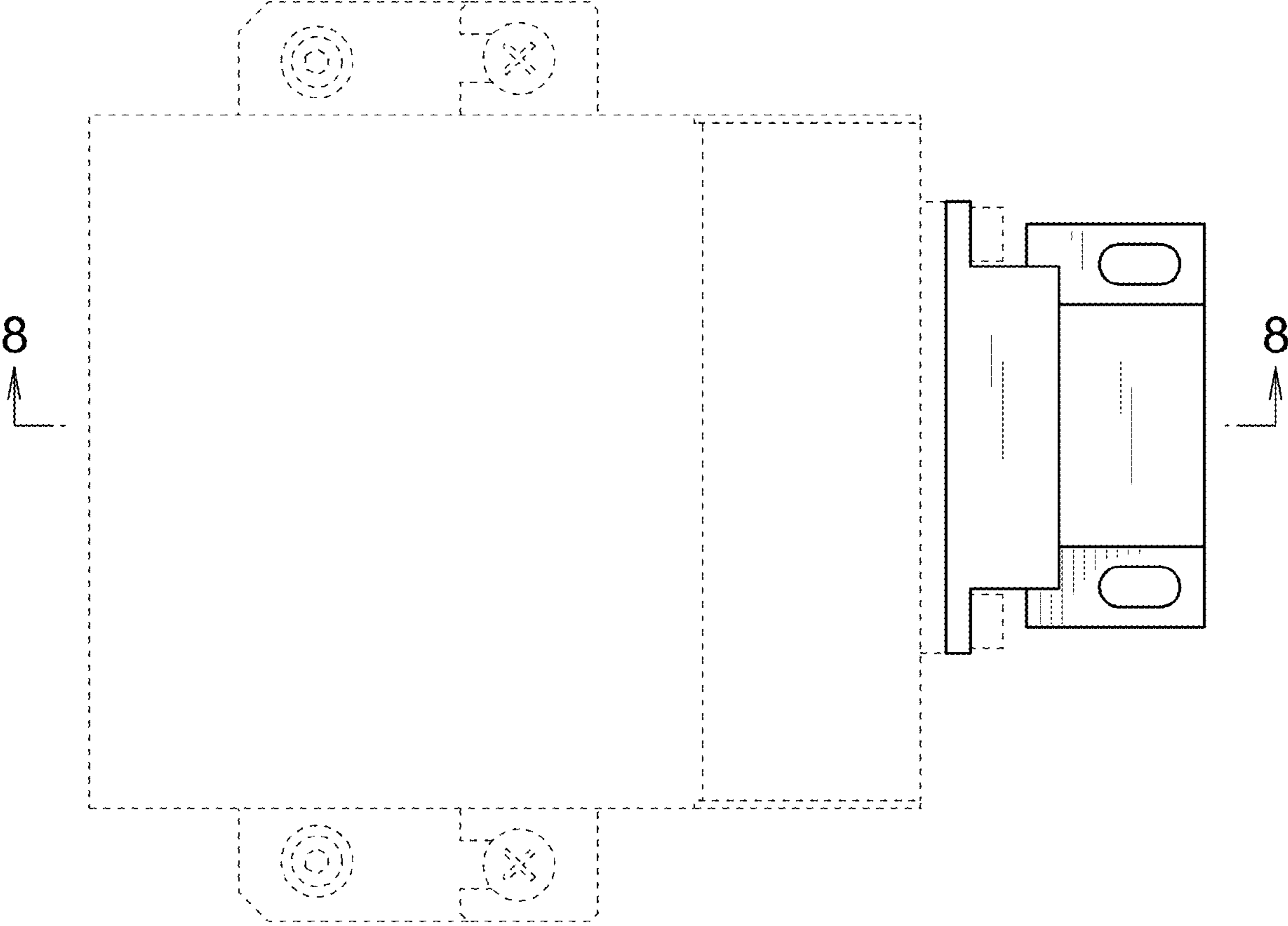


FIG. 2

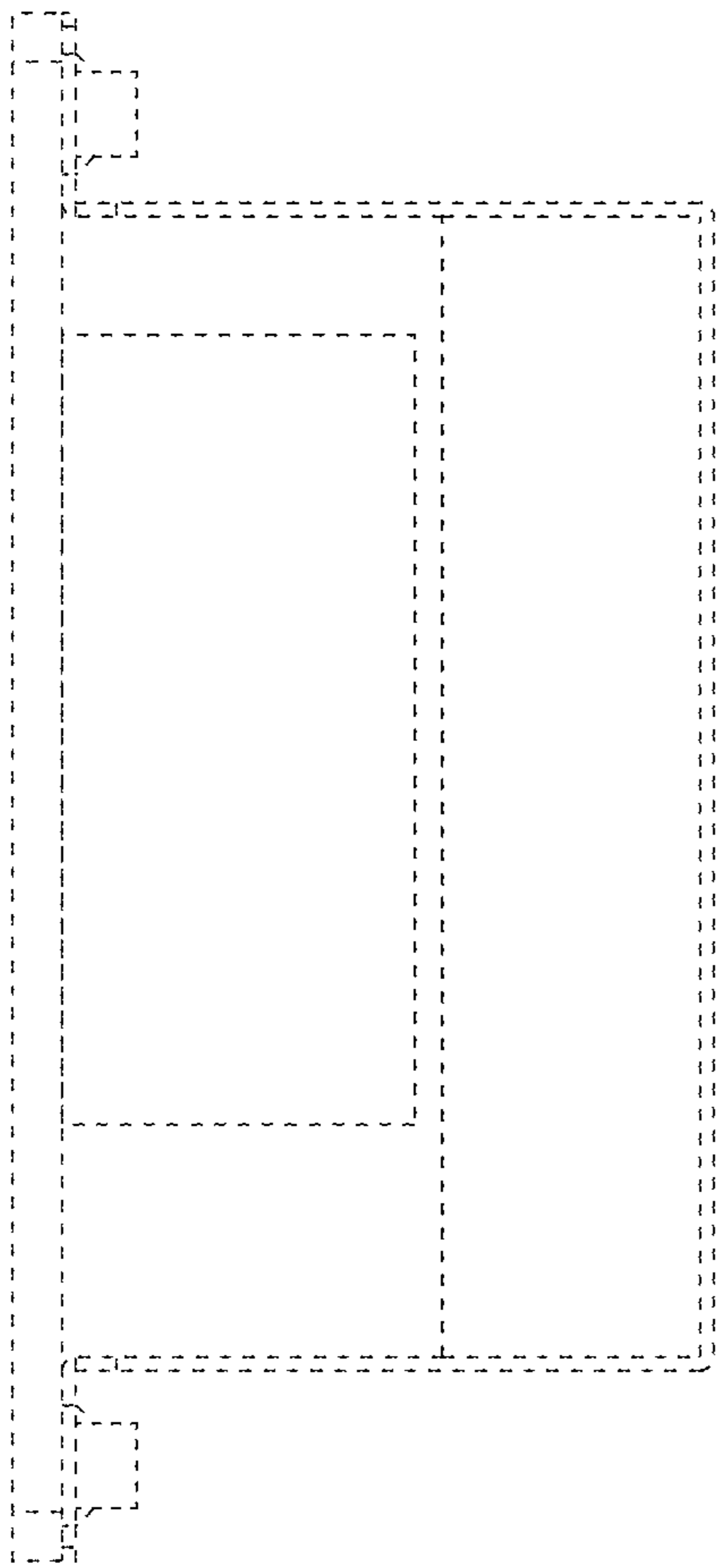


FIG. 3

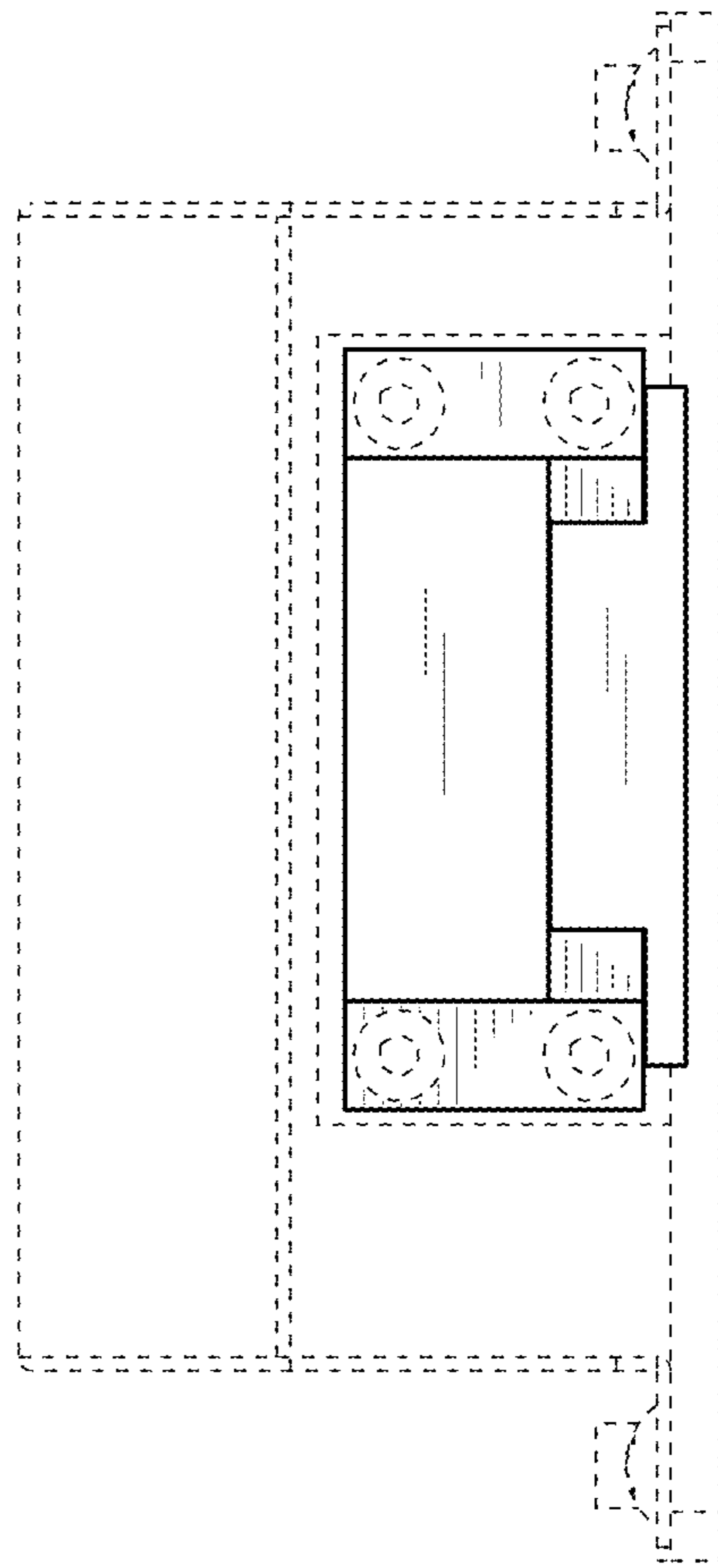
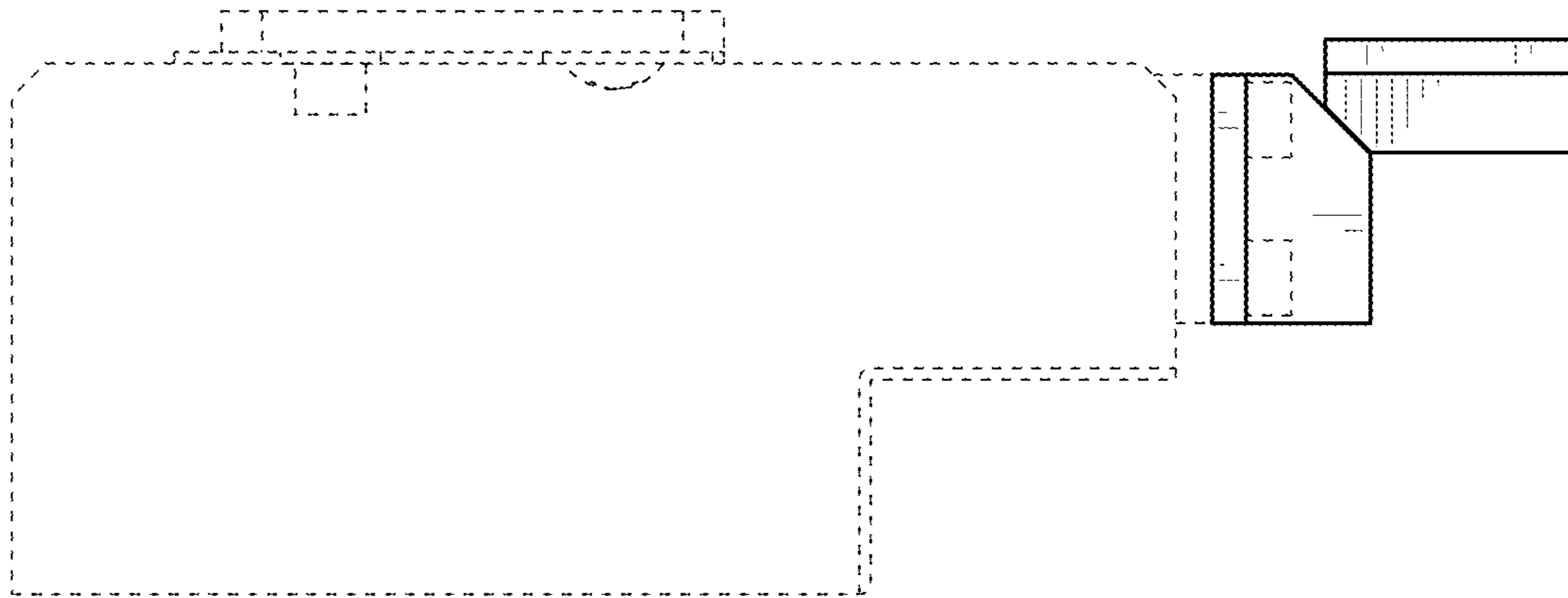
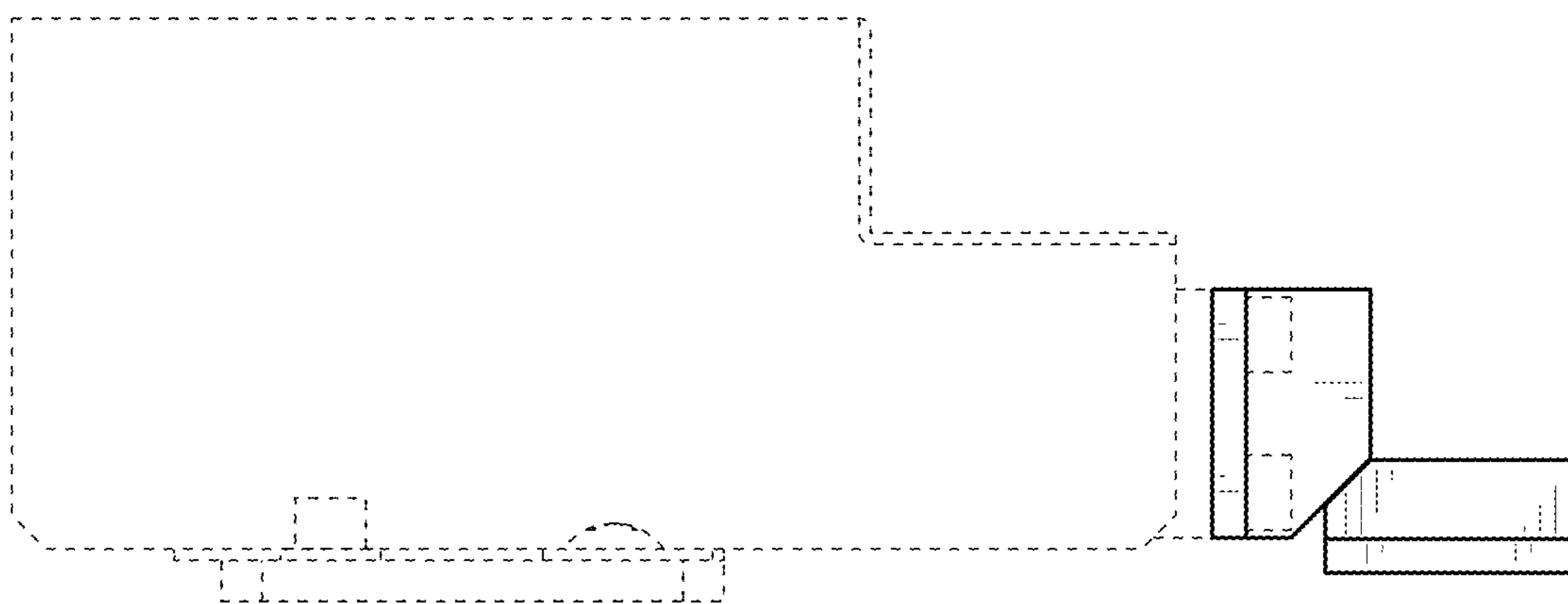


FIG. 4

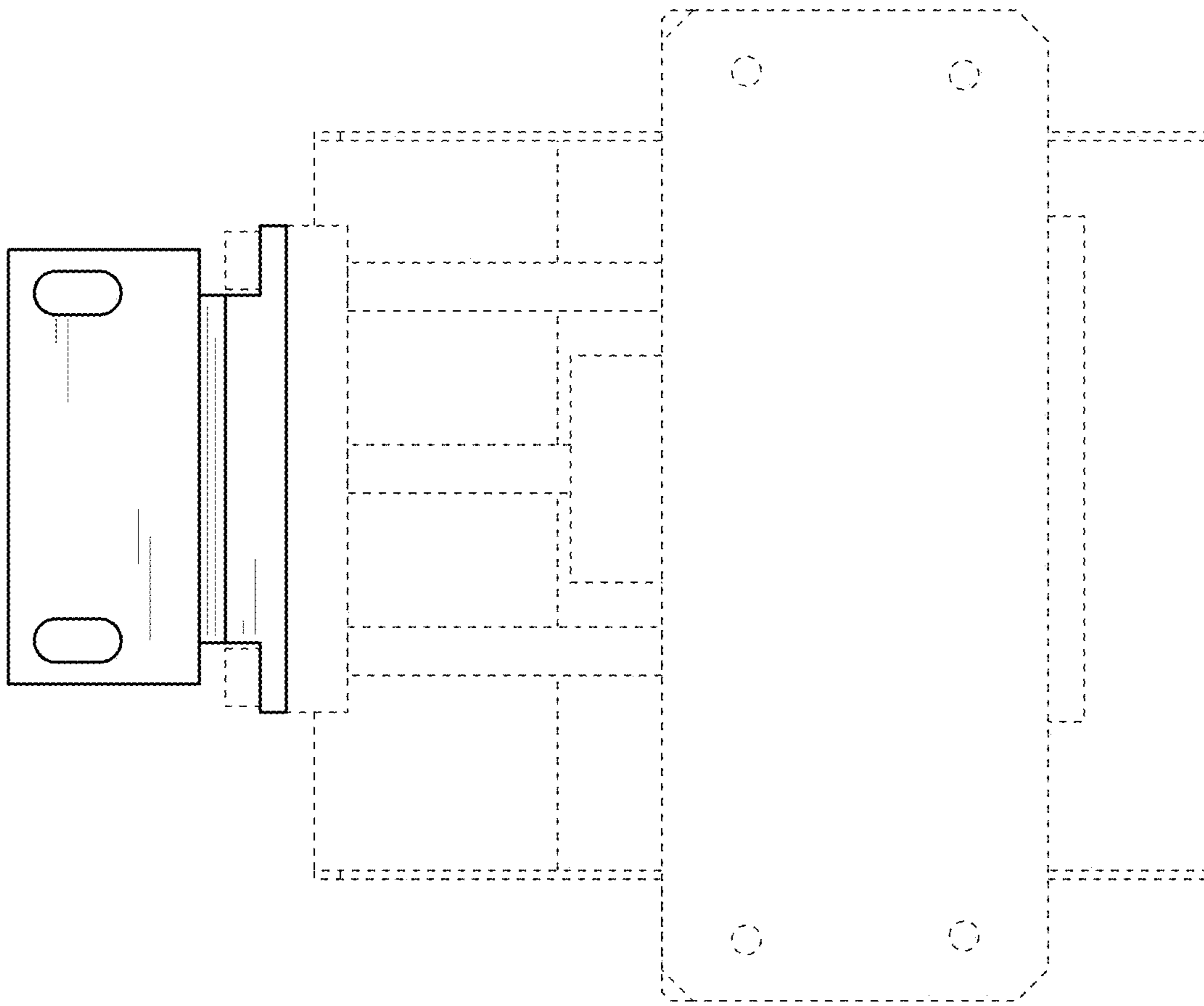


*FIG. 5*

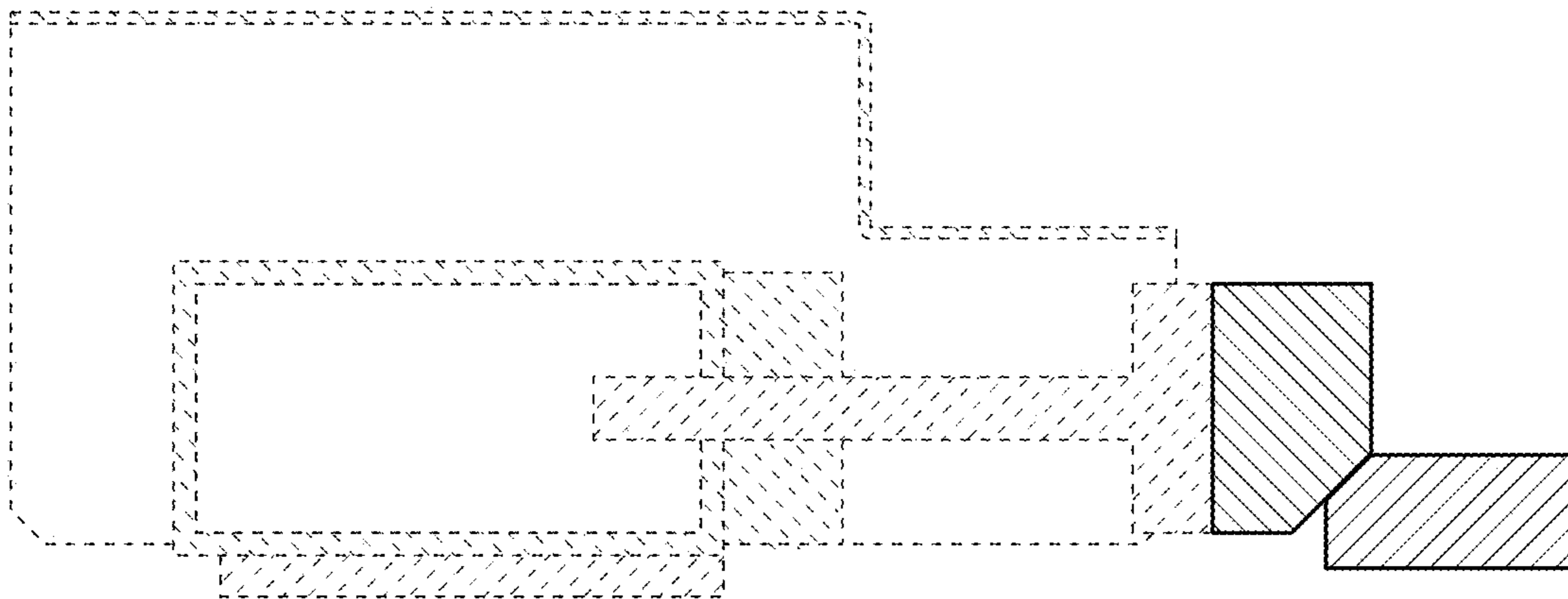


*FIG. 6*





**FIG. 7**



**FIG. 8**

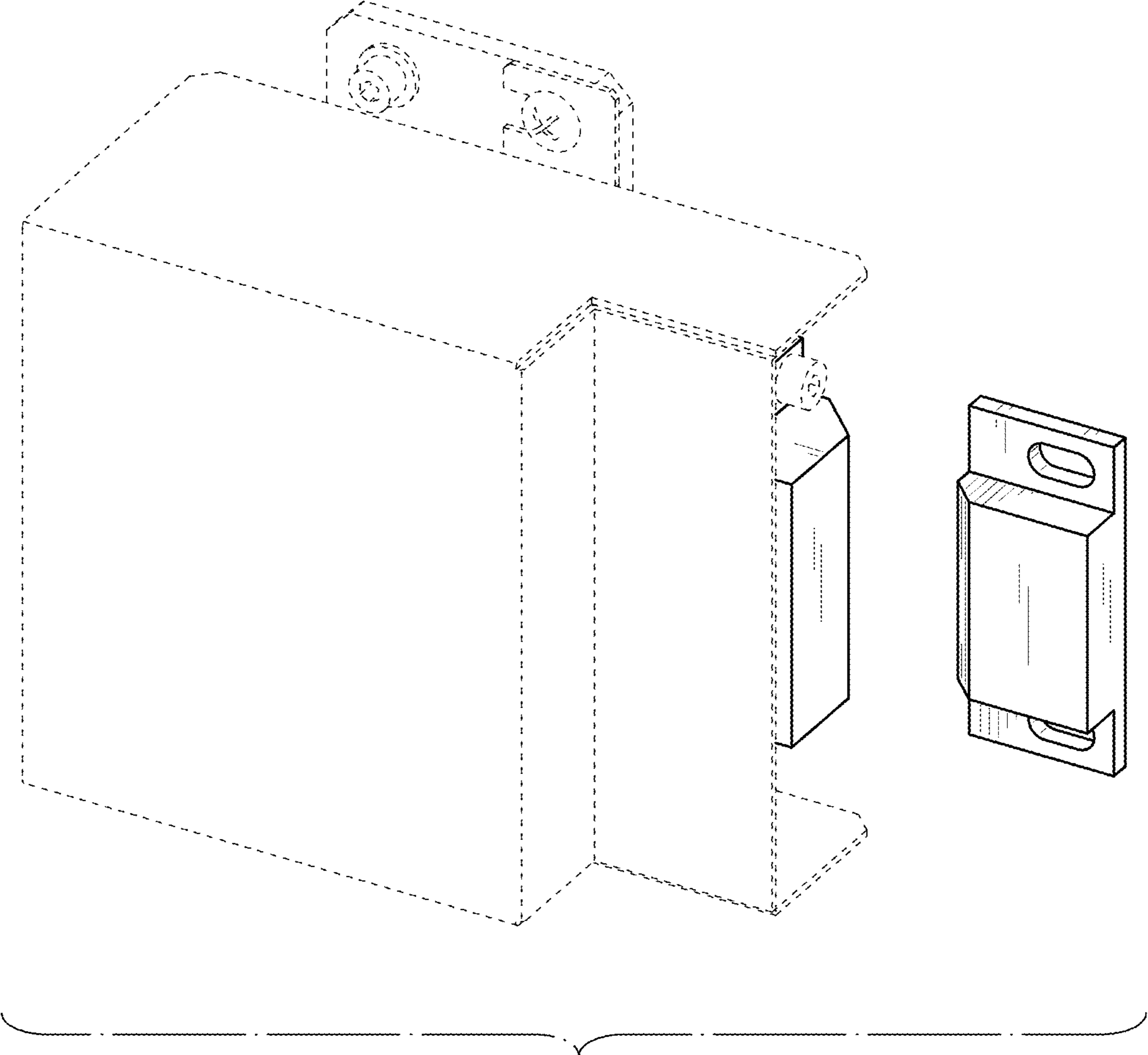


FIG. 9